

## **MOSFET**

## OptiMOS<sup>™</sup> 5 Linear FET, 100 V

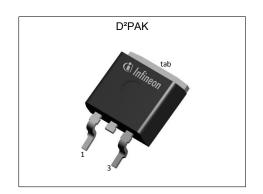
#### **Features**

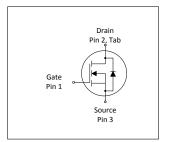
- Ideal for hot-swap and e-fuse applications
- Very low on-resistance R<sub>DS(on)</sub>
  Wide safe operating area SOA
  N-channel, normal level

- 100% avalanche tested
- Pb-free plating; RoHS compliant
  Qualified according to JEDEC<sup>1)</sup> for target applications
  Halogen-free according to IEC61249-2-21



Parameter	Value	Unit
V <sub>DS</sub>	100	V
R <sub>DS(on),max</sub>	3.3	mΩ
$I_{D}$	159	A
$I_{\text{pulse}} (V_{\text{DS}} = 56 \text{ V}, t_{\text{p}} = 10 \text{ ms})$	7	A











Type / Ordering Code	Package	Marking	Related Links
IPB033N10N5LF	PG-TO263-3	033N10LF	_

# OptiMOS<sup>™</sup> 5 Linear FET, 100 V



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## OptiMOS<sup>™</sup> 5 Linear FET, 100 V IPB033N10N5LF



## 1 Maximum ratings at $T_A$ =25 °C, unless otherwise specified

Table 2 Maximum ratings

Davamatav	0	Values				Note / Tool Constition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Continuous drain current <sup>1)</sup>	I <sub>D</sub>	- - -	-	159 108 23	A	$V_{\rm GS}$ =10 V, $T_{\rm C}$ =25 °C $V_{\rm GS}$ =10 V, $T_{\rm C}$ =100 °C $V_{\rm GS}$ =10 V, $T_{\rm C}$ =25 °C, $R_{\rm thJA}$ =40 K/W <sup>2)</sup>	
Pulsed drain current <sup>3)</sup>	I <sub>D,pulse</sub>	-	-	636	Α	<i>T</i> <sub>C</sub> =25 °C	
Avalanche energy, single pulse <sup>4)</sup>	<b>E</b> <sub>AS</sub>	-	-	273	mJ	$I_{\rm D}$ =100 A, $R_{\rm GS}$ =25 $\Omega$	
Gate source voltage	V <sub>GS</sub>	-20	-	20	V	-	
Power dissipation	P <sub>tot</sub>	-	-	179	W	<i>T</i> <sub>C</sub> =25 °C	
Operating and storage temperature	$T_{\rm j},~T_{\rm stg}$	-55	-	150	°C	-	

#### 2 Thermal characteristics

Table 3 Thermal characteristics

Devementar	Complete	Values			11	Note / Took Condition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Thermal resistance, junction - case	R <sub>thJC</sub>	-	0.45	0.7	K/W	-	
Device on PCB, minimal footprint	R <sub>thJA</sub>	-	-	62	K/W	-	
Device on PCB, 6 cm² cooling area²)	R <sub>thJA</sub>	-	-	40	K/W	-	

<sup>&</sup>lt;sup>1)</sup> Rating refers to the product only with datasheet specified absolute maximum values, maintaining case temperature as specified. For other case temperatures please refer to Diagram 2. De-rating will be required based on the actual environmental conditions.  $^{2)}$  Device on 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^{2}$  (one layer, 70  $\mu$ m thick) copper area for drain

connection. PCB is vertical in still air.

3) See Diagram 3 for more detailed information

4) See Diagram 13 for more detailed information

## OptiMOS<sup>™</sup> 5 Linear FET, 100 V IPB033N10N5LF



### 3 Electrical characteristics

at T<sub>j</sub>=25 °C, unless otherwise specified

**Table 4** Static characteristics

Daman dam	0	Values					
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	100	-	-	V	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	
Gate threshold voltage	V <sub>GS(th)</sub>	2.5	3.3	4.1	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =150 μA	
Zero gate voltage drain current	I <sub>DSS</sub>	-	1.0 10	10 100	μA	V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	
Gate-source leakage current	I <sub>GSS</sub>	-	2 -2	5 -5	μΑ	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V V <sub>GS</sub> =-10 V, V <sub>DS</sub> =0 V	
Drain-source on-state resistance	R <sub>DS(on)</sub>	-	2.7	3.3	mΩ	V <sub>GS</sub> =10 V, I <sub>D</sub> =100 A	
Gate resistance <sup>1)</sup>	R <sub>G</sub>	-	40	60	Ω	-	
Transconductance <sup>1)</sup>	<b>g</b> fs	23	46	-	S	V <sub>DS</sub>  >2 I <sub>D</sub>  R <sub>DS(on)max</sub> , I <sub>D</sub> =100 A	

Table 5 Dynamic characteristics

Parameter	Ol	Values			11	Nata / Tank Oan distant	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Input capacitance <sup>1)</sup>	Ciss	-	350	460	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =50 V, <i>f</i> =1 MHz	
Output capacitance <sup>1)</sup>	Coss	-	1100	1400	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =50 V, <i>f</i> =1 MHz	
Reverse transfer capacitance	C <sub>rss</sub>	-	13	-	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =50 V, <i>f</i> =1 MHz	
Turn-on delay time	t <sub>d(on)</sub>	-	8	-	ns	$V_{\rm DD}$ =50 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =50 A, $R_{\rm G,ext}$ =1.6 $\Omega$	
Rise time	t <sub>r</sub>	-	32	-	ns	$V_{\rm DD}$ =50 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =50 A, $R_{\rm G,ext}$ =1.6 $\Omega$	
Turn-off delay time	$t_{ m d(off)}$	-	64	-	ns	$V_{\rm DD}$ =50 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =50 A, $R_{\rm G,ext}$ =1.6 $\Omega$	
Fall time	t <sub>f</sub>	-	48	-	ns	$V_{\rm DD}$ =50 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =50 A, $R_{\rm G,ext}$ =1.6 $\Omega$	

Table 6 Gate charge characteristics<sup>2)</sup>

Parameter	Symbol	Values			Unit	Note / Test Condition	
Parameter	Symbol	Min.	Тур.	Max.	Oilit	Note / Test Condition	
Gate to source charge	Q <sub>gs</sub>	-	3	-	nC	$V_{DD}$ =50 V, $I_{D}$ =100 A, $V_{GS}$ =0 to 10 V	
Gate to drain charge	Q <sub>gd</sub>	-	72	-	nC	$V_{DD}$ =50 V, $I_{D}$ =100 A, $V_{GS}$ =0 to 10 V	
Gate charge total	Qg	-	102	-	nC	$V_{DD}$ =50 V, $I_{D}$ =100 A, $V_{GS}$ =0 to 10 V	
Gate plateau voltage	V <sub>plateau</sub>	-	6.9	-	V	V <sub>DD</sub> =50 V, I <sub>D</sub> =100 A, V <sub>GS</sub> =0 to 10 V	
Output charge <sup>1)</sup>	Qoss	-	116	155	nC	V <sub>DD</sub> =50 V, V <sub>GS</sub> =0 V	

 $<sup>^{1)}</sup>$  Defined by design. Not subject to production test.  $^{2)}$  See "Gate charge waveforms" for parameter definition

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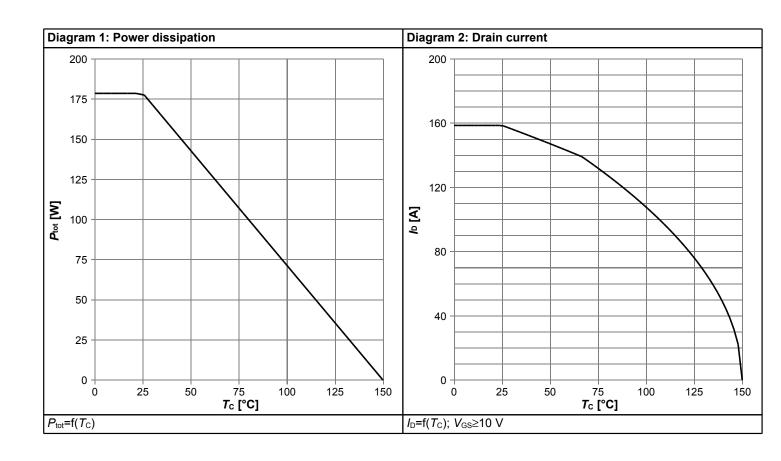


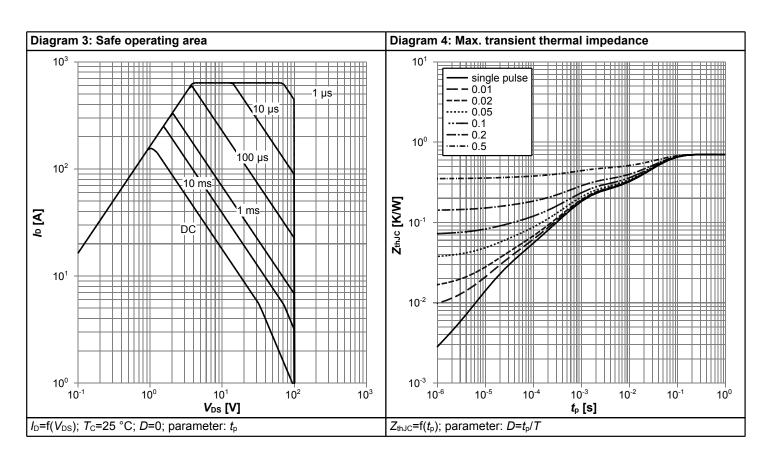
### Table 7 Reverse diode

Davamatau	Cymphal		Values			Note / Took Open little	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Diode continuous forward current	Is	-	-	133	Α	<i>T</i> <sub>C</sub> =25 °C	
Diode pulse current	I <sub>S,pulse</sub>	-	-	636	Α	T <sub>C</sub> =25 °C	
Diode forward voltage	<b>V</b> <sub>SD</sub>	-	0.93	1.2	V	V <sub>GS</sub> =0 V, I <sub>F</sub> =100 A, T <sub>j</sub> =25 °C	
Reverse recovery time	<i>t</i> <sub>rr</sub>	-	58	-	ns	$V_R$ =50 V, $I_F$ =50A, $di_F/dt$ =100 A/ $\mu$ s	
Reverse recovery charge	Qrr	-	94	-	nC	$V_R$ =50 V, $I_F$ =50A, $d_F/dt$ =100 A/ $\mu$ s	

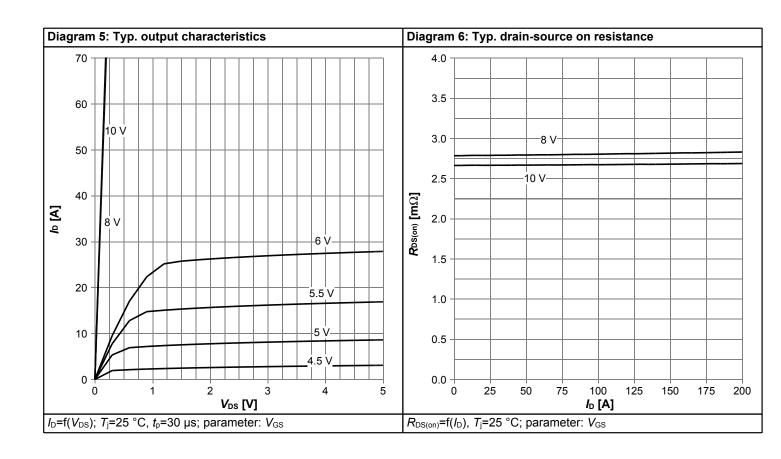


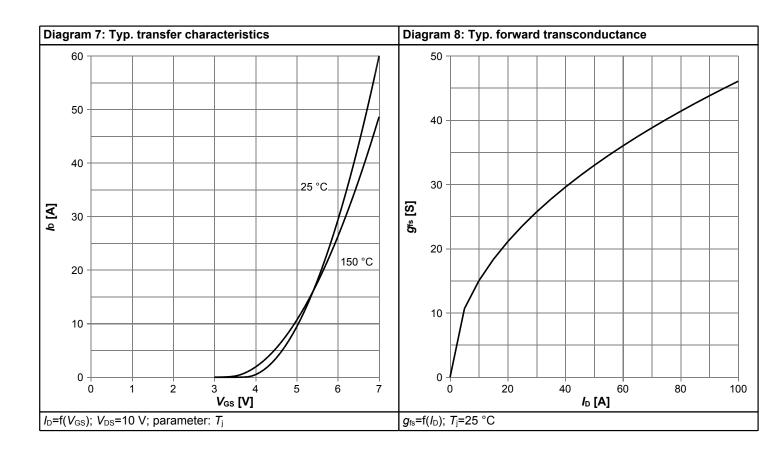
## 4 Electrical characteristics diagrams



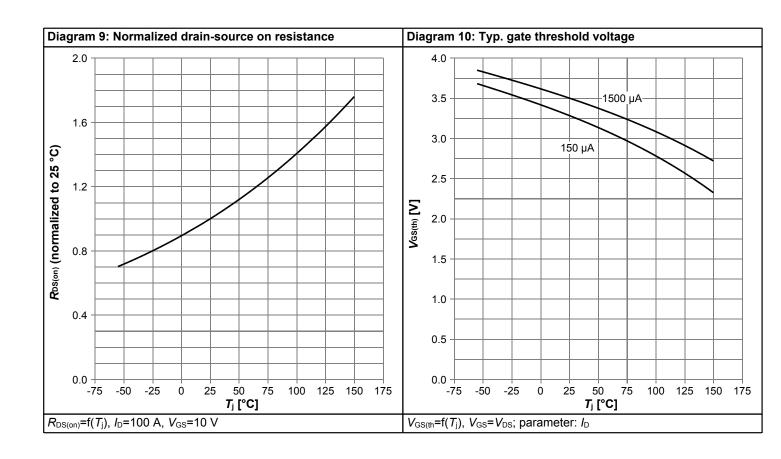


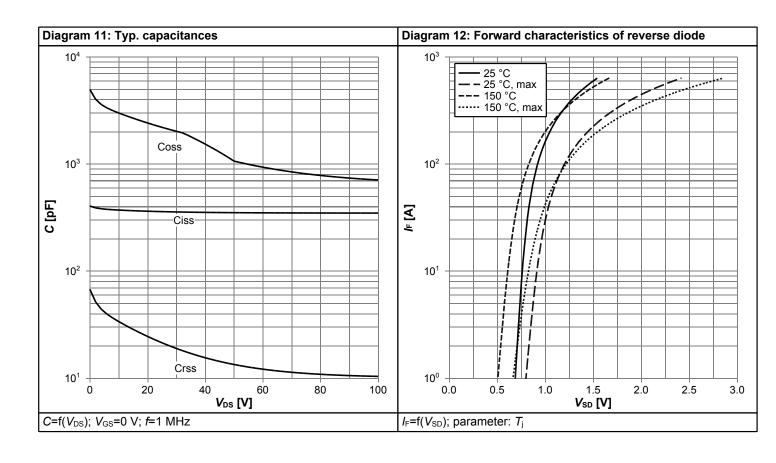




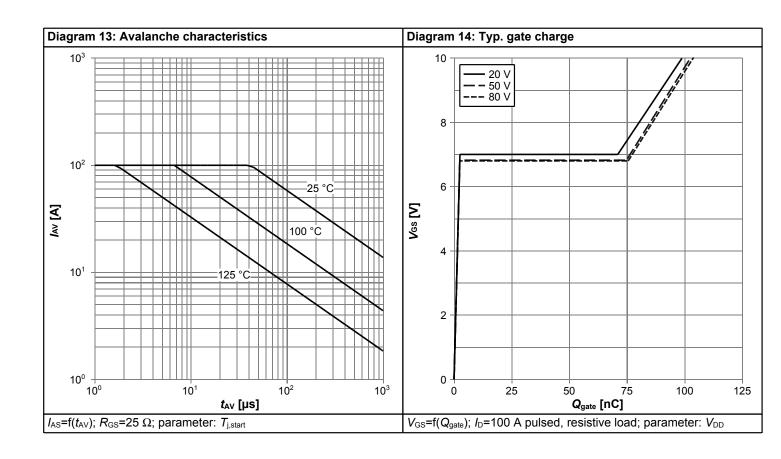


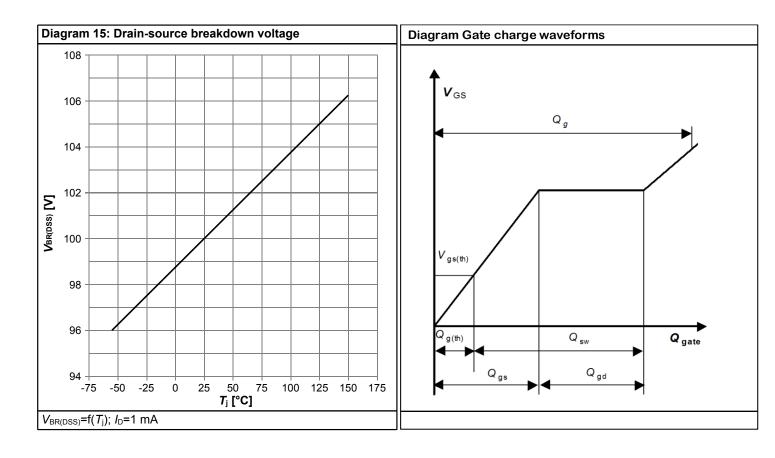






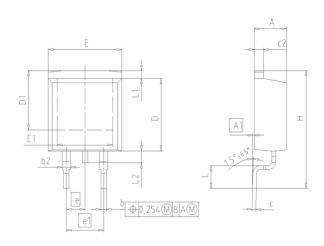


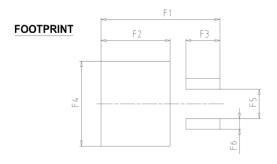






## 5 Package Outlines





DIM	MILLI	METERS	INCI	HES		
DIM	MIN	MAX	MIN	MAX		
Α	4.30	4.57	0.169	0.180		
A1	0.00	0.25	0.000	0.010		
b	0.65	0.85	0.026	0.033		
b2	0.95	1.15	0.037	0.045		
С	0.33	0.65	0.013	0.026		
c2	1.17	1.40	0.046	0.055		
D	8.51	9.45	0.335	0.372		
D1	7.10	7.90	0.280	0.311		
E	9.80	10.31	0.386	0.406		
E1	6.50	8.60	0.256	0.339		
е	2.	.54	0.100			
e1	5.	.08	0.200			
N		2	2			
Н	14.61	15.88	0.575	0.625		
L	2.29	3.00	0.090	0.118		
L1	0.70	1.60	0.028	0.063		
L2	1.00	1.78	0.039	0.070		
F1	16.05	16.25	0.632	0.640		
F2	9.30	9.50	0.366	0.374		
F3	4.50	4.70	0.177	0.185		
F4	10.70	10.90	0.421	0.429		
F5	3.65	3.85	0.144	0.152		
F6	1.25	1.45	0.049	0.057		

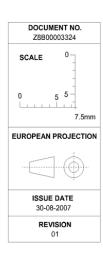


Figure 1 Outline PG-TO263-3, dimensions in mm/inches

## OptiMOS<sup>™</sup> 5 Linear FET, 100 V



#### **Revision History**

IPB033N10N5LF

Revision: 2022-06-23, Rev. 2.2

Previous Revision

1 1CVIOUS I	CVISION	
Revision	Date	Subjects (major changes since last revision)
2.0	2016-12-15	Release of final version
2.1	2017-02-16	Update technology heading
2.2	2022-06-23	Update current rating, footnotes and skip "Operating and storage temperature" condition

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